

54ABT/74ABT377C

Octal D-Type Flip-Flop with Clock Enable

General Description

The 'ABT377C has eight edge-triggered, D-type flip-flops with individual D inputs and Q outputs. The common buffered Clock (CP) input loads all flip-flops simultaneously, when the Clock Enable (CE) is LOW.

The register is fully edge-triggered. The state of each D input, one setup time before the LOW-to-HIGH clock transition, is transferred to the corresponding flip-flop's Q output. The CE input must be stable only one setup time prior to the LOW-to-HIGH clock transition for predictable operation.

Features

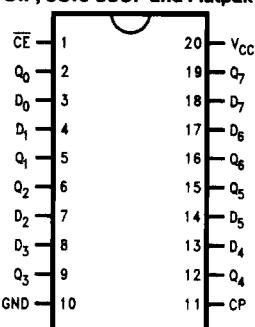
- Clock enable for address and data synchronization applications

- Eight edge-triggered D flip-flops
- Buffered common clock
- See 'ABT273C for master reset version
- See 'ABT373C for transparent latch version
- See 'ABT374C for TRI-STATE® version
- Output sink capability of 64 mA, source capability of 32 mA
- Guaranteed 2000V minimum ESD protection
- Guaranteed latchup protection
- High impedance glitch free bus loading during entire power up and power down cycle
- Non-destructive hot insertion capability
- Disable time less than enable time to avoid bus contention

Ordering Code: See Section 10

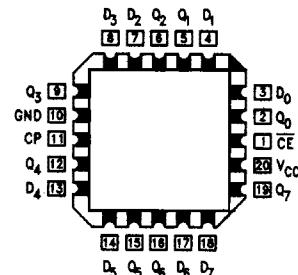
Connection Diagrams

Pin Assignment for
DIP, SOIC SSOP and Flatpak



TL/F/11550-1

Pin Assignment
for LCC



TL/F/11550-2

Pin Names	Description
D ₀ -D ₇	Data Inputs
CE	Clock Enable (Active LOW)
CP	Clock Pulse Input
Q ₀ -Q ₇	Data Outputs

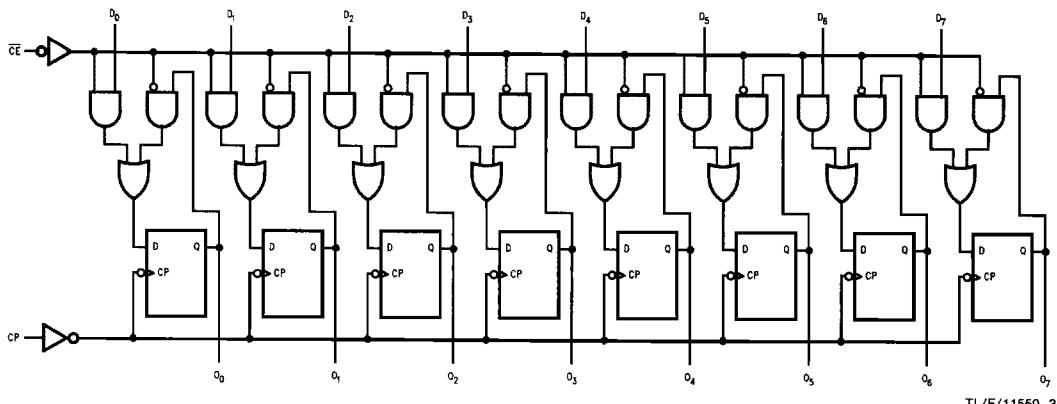
Truth Table

Mode Select-Function Table

Operating Mode	Inputs			Output Q_n
	CP	\overline{CE}	D_n	
Load "1"	/	I	h	H
Load "0"	/	I	I	L
Hold (Do Nothing)	/	h	X	No Change
	X	H	X	No Change

H = HIGH Voltage Level
 h = HIGH Voltage Level one setup time prior to the LOW-to-HIGH Clock Transition
 L = LOW Voltage Level
 I = LOW Voltage Level one setup time prior to the LOW-to-HIGH Clock Transition
 X = Immaterial
 / = LOW-to-HIGH Clock Transition

Logic Diagram



TL/F/11550-3

Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Storage Temperature	–65°C to +150°C
Ambient Temperature under Bias	–55°C to +125°C
Junction Temperature under Bias	
Ceramic	–55°C to +175°C
Plastic	–55°C to +150°C
V _{CC} Pin Potential to Ground Pin	–0.5V to +7.0V
Input Voltage (Note 2)	–0.5V to +7.0V
Input Current (Note 2)	–30 mA to +5.0 mA
Voltage Applied to Any Output in the Disabled or Power-Off State	–0.5V to +4.75V
in the HIGH State	–0.5V to V _{CC}
Current Applied to Output in LOW State (Max)	Twice the rated I _{OL} (mA)

ESD Last Passing Voltage (Min)	2000V
DC Latchup Source Current	–500 mA
Over Voltage Latchup	V _{CC} + 4.5V

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

Recommended Operating Conditions

Free Air Ambient Temperature	
Military	–55°C to +125°C
Commercial	–40°C to +85°C
Supply Voltage	
Military	+4.5V to +5.5V
Commercial	+4.5V to +5.5V
Minimum Input Edge Rate	(ΔV/Δt)
Data Input	50 mV/ns
Enable Input	20 mV/ns

DC Electrical Characteristics

Symbol	Parameter	ABT377C			Units	V _{CC}	Conditions
		Min	Typ	Max			
V _{IH}	Input HIGH Voltage	2.0			V		Recognized HIGH Signal
V _{IL}	Input LOW Voltage			0.8	V		Recognized LOW Signal
V _{CD}	Input Clamp Diode Voltage			–1.2	V	Min	I _{IN} = –18 mA
V _{OH}	Output HIGH Voltage 54ABT/74ABT	2.5			V	Min	I _{OH} = –3 mA I _{OH} = –24 mA I _{OH} = –32 mA
V _{OH}	54ABT	2.0					
V _{OH}	74ABT	2.0					
V _{OL}	Output LOW Voltage 54ABT	0.55			V	Min	I _{OL} = 48 mA
V _{OL}	74ABT	0.55					I _{OL} = 64 mA
I _{IH}	Input HIGH Current		5	5	μA	Max	V _{IN} = 2.7V (Note 2) V _{IN} = V _{CC}
I _{BVI}	Input HIGH Current Breakdown Test			7	μA	Max	V _{IN} = 7.0V
I _{IL}	Input LOW Current		–5	–5	μA	Max	V _{IN} = 0.5V (Note 2) V _{IN} = 0.0V
V _{ID}	Input Leakage Test	4.75			V	0.0	I _{ID} = 1.9 μA All Other Pins Grounded
I _{OS}	Output Short-Circuit Current	–100	–275	mA	Max		V _{OUT} = 0.0V
I _{CEX}	Output High Leakage Current		50	μA	Max		V _{OUT} = V _{CC}
I _{CCH}	Power Supply Current		50	μA	Max		All Outputs HIGH
I _{CCL}	Power Supply Current		30	mA	Max		All Outputs LOW
I _{CCT}	Maximum I _{CC} /Input Outputs Enabled		2.5	mA	Max		V _I = V _{CC} – 2.1V Data Input V _I = V _{CC} – 2.1V All Others at V _{CC} or GND
I _{CCD}	Dynamic I _{CC} No Load		0.1	mA/MHz	Max		Outputs Open (Note 1) One bit Toggling, 50% Duty Cycle

Note 1: For 8 bits toggling, I_{CCD} < 0.5 mA/MHz.

Note 2: Guaranteed but not tested.

AC Electrical Characteristics: See Section 2 (SOIC package, contact factory for DIP or SSOP)

Symbol	Parameter	74ABTC			54ABTC			74ABTC			Units	Fig. No.		
		$T_A = +25^\circ C$ $V_{CC} = +5.0V$ $C_L = 50 pF$			$T_A = -55^\circ C \text{ to } +125^\circ C$ $V_{CC} = 4.5V \text{ to } 5.5V$ $C_L = 50 pF$			$T_A = -40^\circ C \text{ to } +85^\circ C$ $V_{CC} = 4.5V \text{ to } 5.5V$ $C_L = 50 pF$						
		Min	Typ	Max	Min	Max	Min	Max	Min	Max				
f_{max}	Max Clock Frequency										MHz			
t_{PLH}	Propagation Delay CP to O_n	2.2	6.5				2.2	6.5	3.1	7.3	ns	2-3, 5		
t_{PHL}		3.1	7.3											

AC Operating Requirements: See Section 2 for Waveforms

Symbol	Parameter	74ABTC			54ABTC			74ABTC			Units	Fig. No.		
		$T_A = +25^\circ C$ $V_{CC} = +5.0V$ $C_L = 50 pF$			$T_A = -55^\circ C \text{ to } +125^\circ C$ $V_{CC} = 4.5V \text{ to } 5.5V$ $C_L = 50 pF$			$T_A = -40^\circ C \text{ to } +85^\circ C$ $V_{CC} = 4.5V \text{ to } 5.5V$ $C_L = 50 pF$						
		Min	Max	Min	Max	Min	Max	Min	Max	Min				
$t_s(H)$	Setup Time, HIGH	2.0					2.0				ns	2-6		
$t_s(L)$	or LOW D_n to CP	2.0					2.0							
$t_h(H)$	Hold Time, HIGH	1.8					1.8				ns	2-6		
$t_h(L)$	or LOW D_n to CP	1.8					1.8							
$t_s(H)$	Setup Time, HIGH	3.0					3.0				ns	2-6		
$t_s(L)$	or LOW \bar{CE} to CP	3.0					3.0							
$t_h(H)$	Hold Time, HIGH	1.8					1.8				ns	2-6		
$t_h(L)$	or LOW \bar{CE} to CP	1.8					1.8							
$t_w(H)$	Pulse Width, CP,	3.3					3.3				ns	2-3		
$t_w(L)$	HIGH or LOW	3.3					3.3							

Capacitance (SOIC package, contact factory for DIP or SSOP) (Note 3)

Symbol	Parameter	Typ	Units	Conditions
C_{IN}	Input Capacitance	5	pF	$V_{CC} = 0V, T_A = 25^\circ C$
C_{OUT} (Note 1)	Output Capacitance	9	pF	$V_{CC} = 5.0V$

Note 1: C_{OUT} is measured at frequency $f = 1$ MHz, per MIL-STD-883B, Method 3012.